

# EUROPEAN PATENT OFFICE

## Patent Abstracts of Japan

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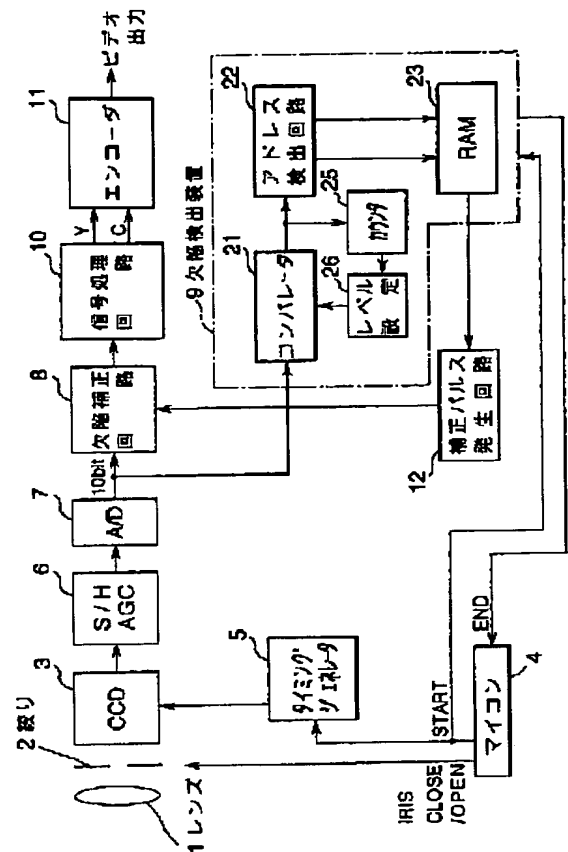
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TITLE : DEFECT DETECTING DEVICE FOR  
SOLID-STATE IMAGE PICKUP  
ELEMENT, AND DEFECT  
CORRECTING DEVICE USING SAME



ABSTRACT : PURPOSE: To provide the defect detecting device for a solid-state image pickup element, and the defect correcting device using the same, by which a defect can be detected efficiently extending over the whole screen by using effectively a memory of a limited storage capacity.

CONSTITUTION: At the time of executing a defect inspection, a defective picture element is detected by comparing an image pickup output level of a CCD solid- state image pickup element 3 with a prescribed detection level by a comparator 21, the detected number of defective pixels is counted by a counter 25, and when the detected number exceeds the storage allowable number of a RAM 23, the defect detection sensitivity is lowered by setting the detection level of the comparator higher than the previous one by a detection level setting circuit 26, and a re-inspection is repeated until the number of defective pixels is held in the allowable number.

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